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United States Patent [19]

Kaise et al.

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[45] **Date of Patent: ** Jan. 25, 2000**

[54] **CLAMP TESTER**

[75] Inventors: **Hideo Kaise**; **Etsuo Shirai**, both of Ueda, Japan

[73] Assignee: **Kaise Kabushiki Kaisha**, Nagano-ken, Japan

[**] Term: **14 Years**

[21] Appl. No.: **29/103,258**

[22] Filed: **Apr. 12, 1999**

[51] **LOC (7) Cl.** **10-04**

[52] **U.S. Cl.** **D10/79**

[58] **Field of Search** .... D10/79; 324/73 R, 324/73 S, 114, 115, 117, 116, 126, 127, 128, 129, 133, 149, 158 F, 158 P; 336/175, 212

[56] **References Cited**

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[57] **CLAIM**

The ornamental design for a clamp tester, as shown and described.

DESCRIPTION

FIG. **1** is a perspective view of a clamp tester showing my new design;
FIG. **2** is a front elevational view thereof;
FIG. **3** is a rear elevational view thereof;
FIG. **4** is a left side elevational view thereof;
FIG. **5** is a right side elevational view thereof;
FIG. **6** is a top plan view thereof;
FIG. **7** is a bottom plan view thereof; and,
FIG. **8** is a front elevational view indicating a clamp-open status.

1 Claim, 4 Drawing Sheets

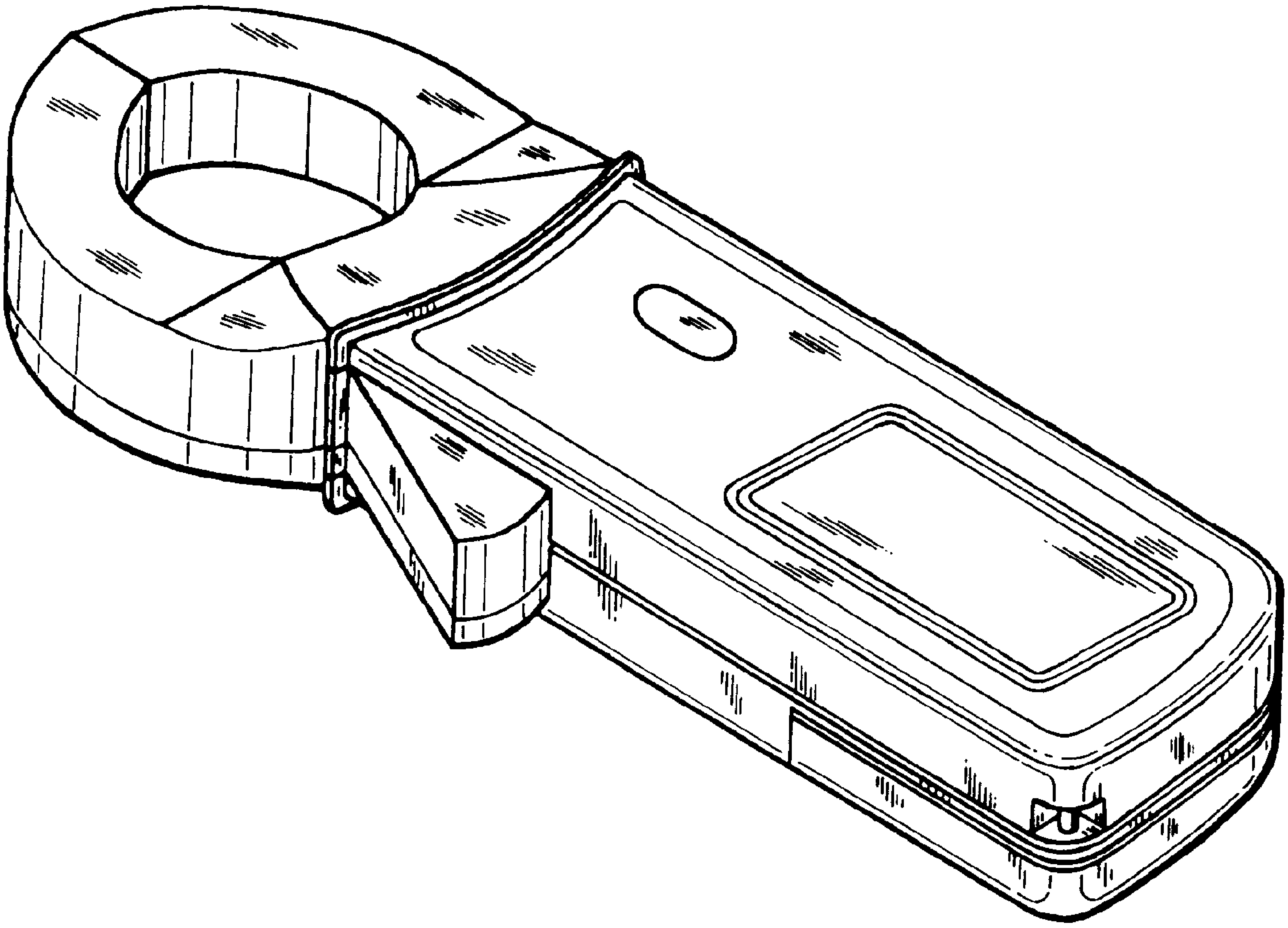


FIG.1

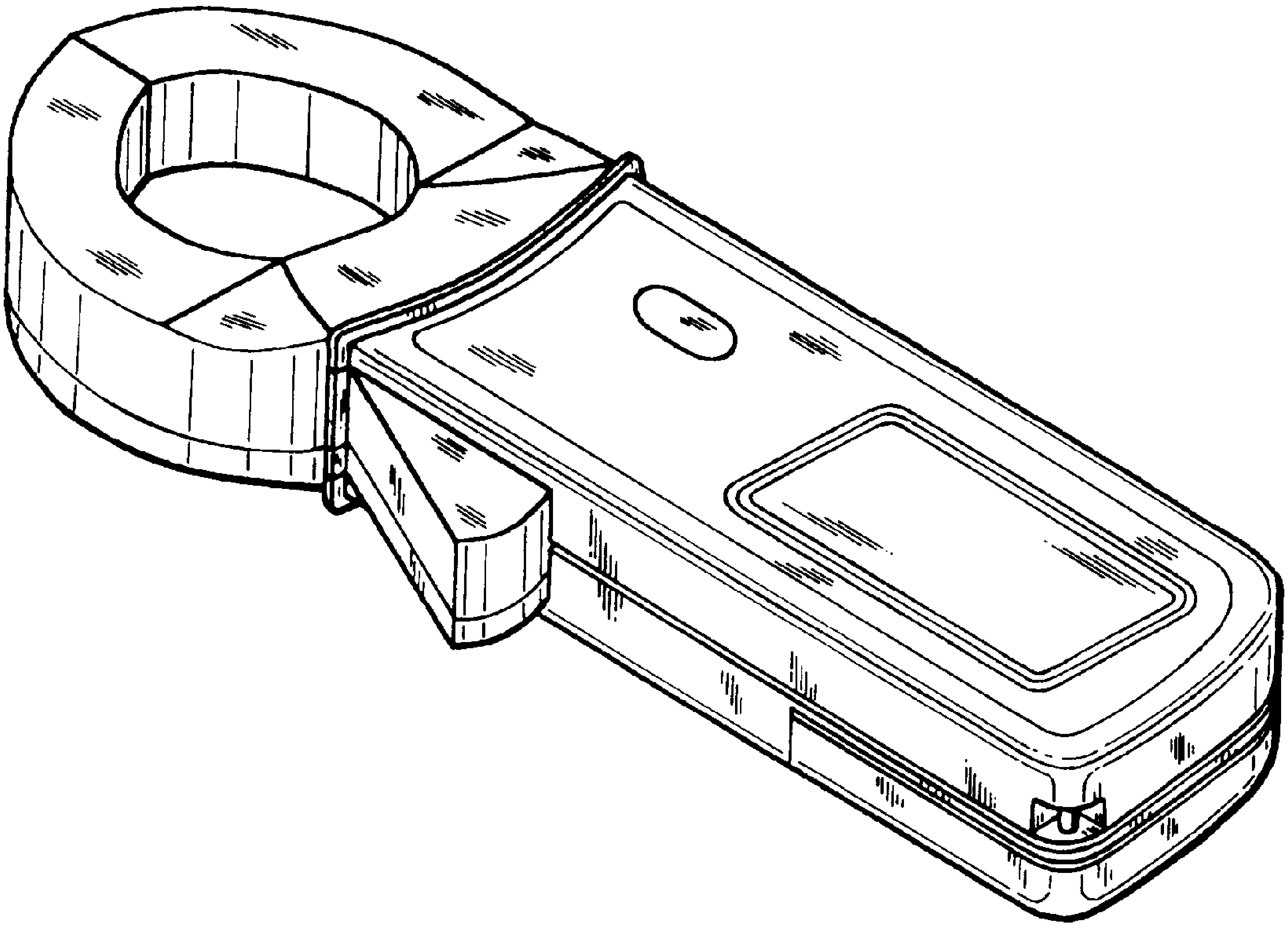


FIG. 2

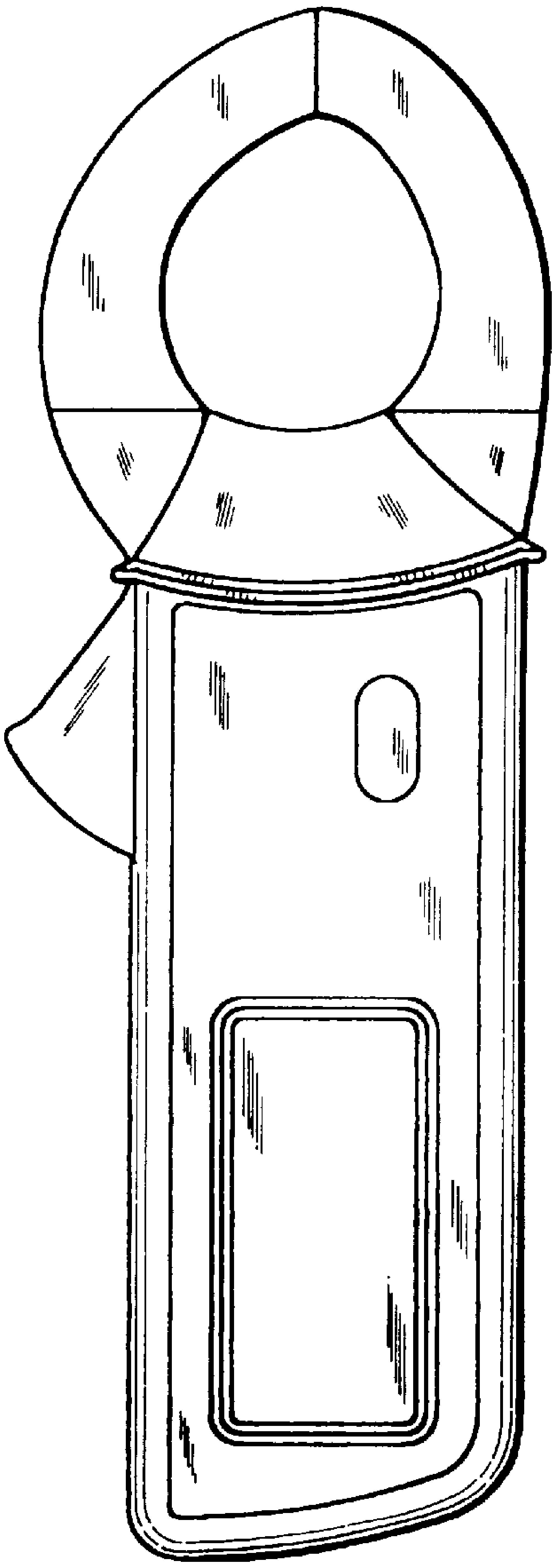


FIG. 3

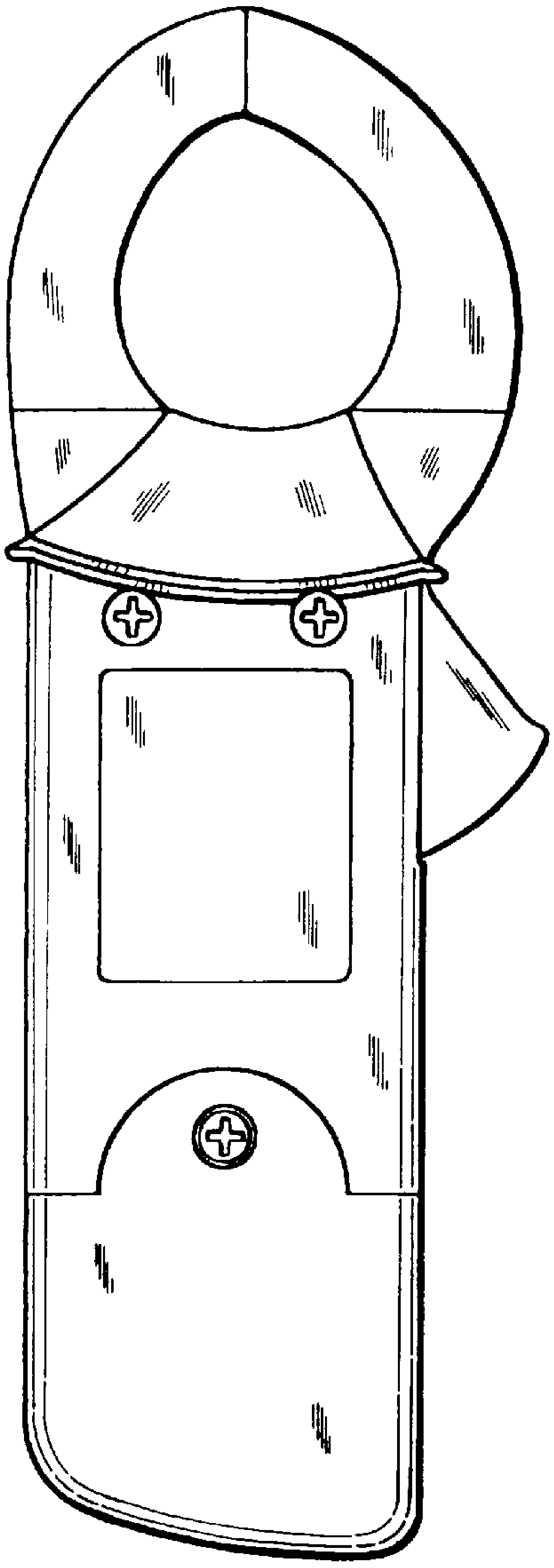


FIG.4

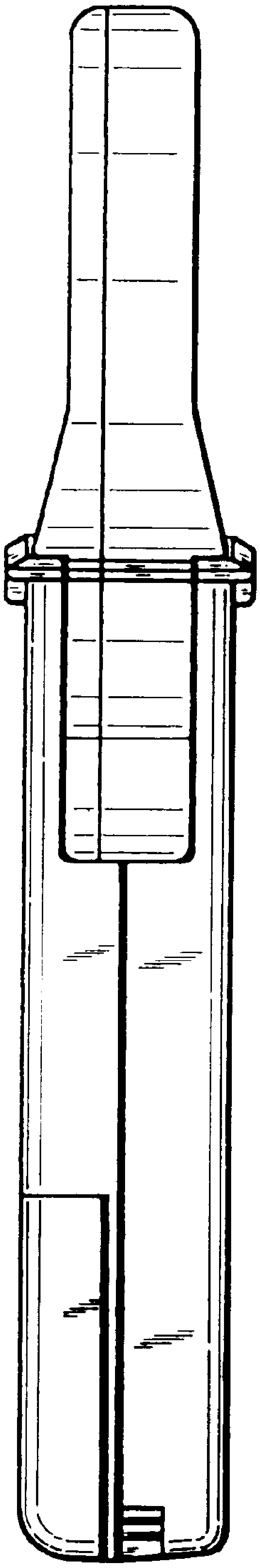
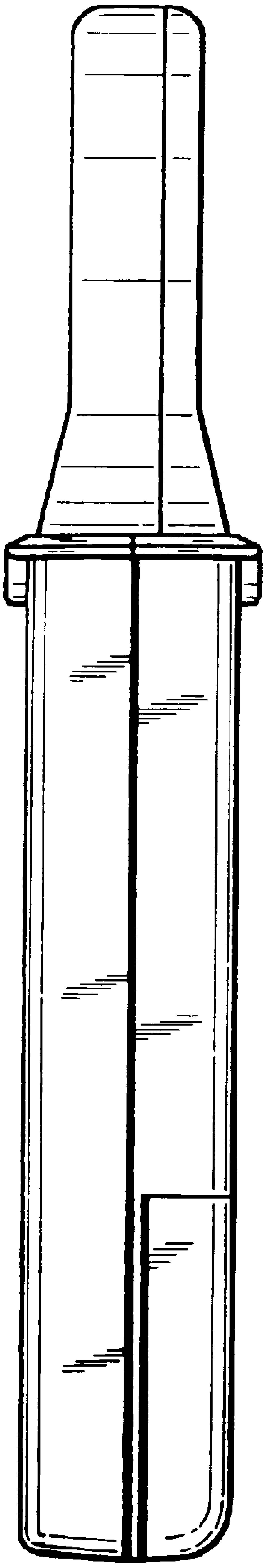


FIG.5



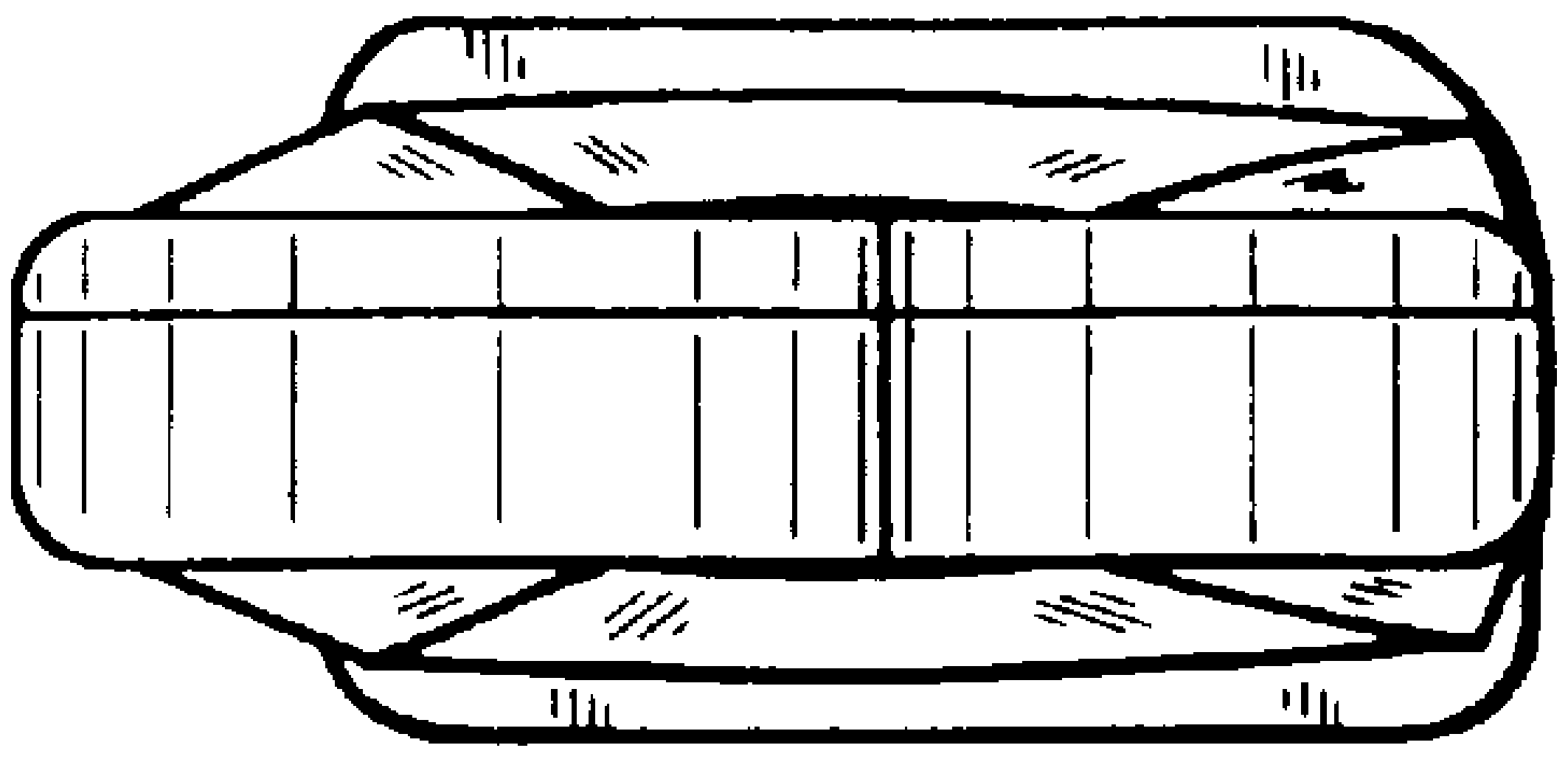


FIG.6

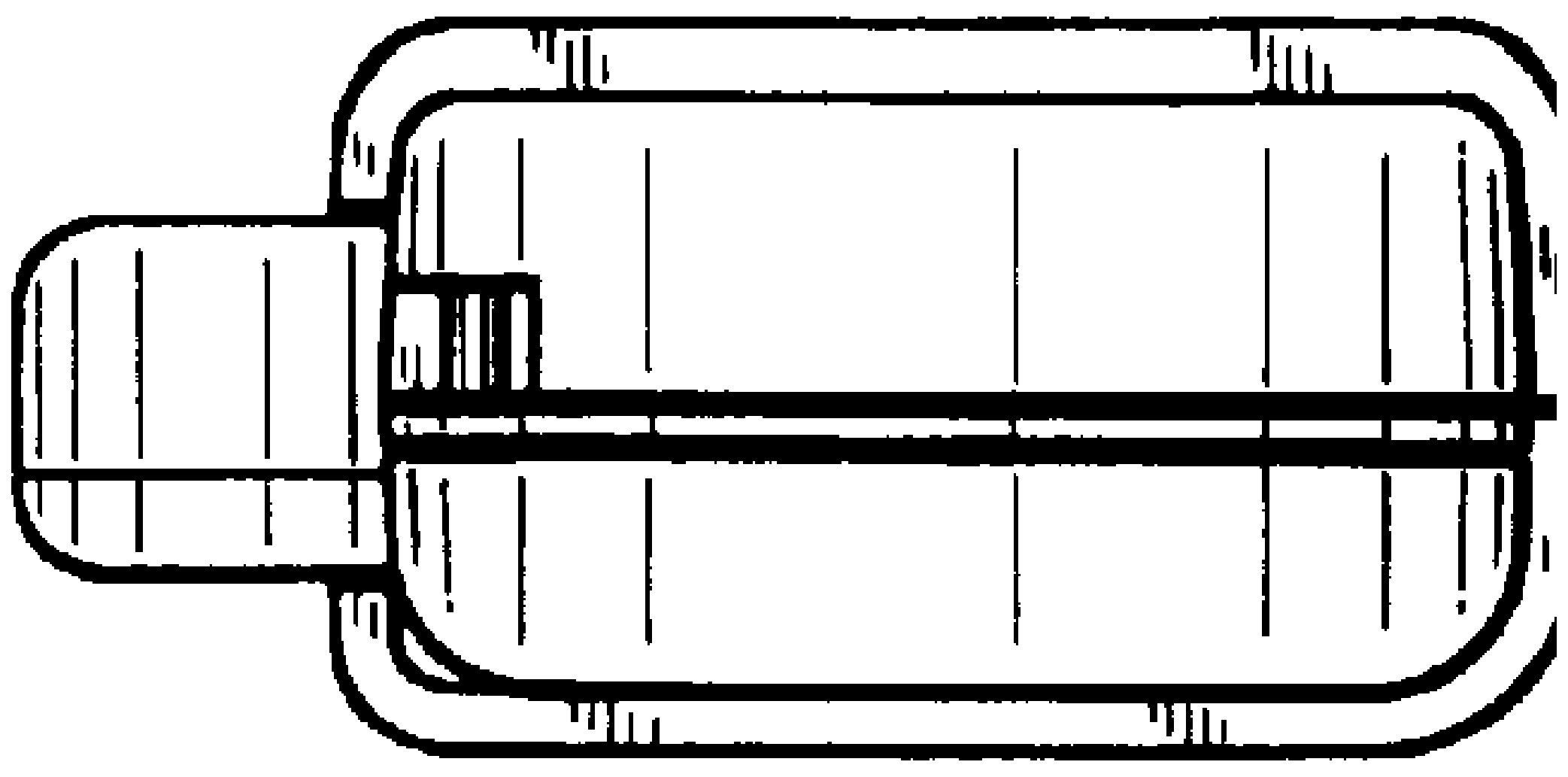


FIG.7

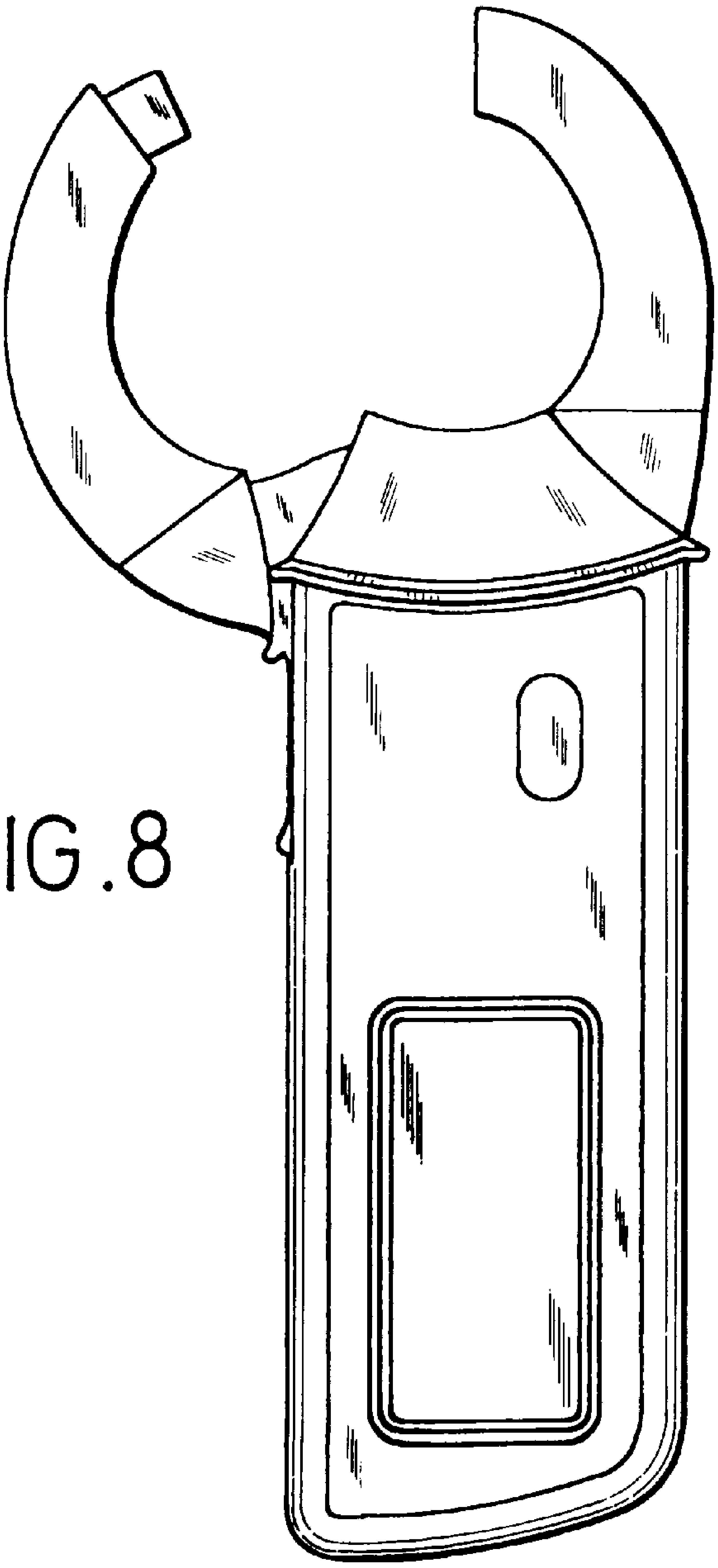


FIG.8